

#### APPLICATION FOR ELECTROMAGNETIC COMPATIBILITY DIRECTIVE

On Behalf of

# Shenzhen Yostand Technology Co., Ltd.

Infrared Thermometer

## Model No.: ET01

Prepared for	:	Shenzhen Yostand Technology Co., Ltd.
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### TABLE OF CONTENTS

De	escript	tion	Page
1.	Sum	mary Of Standards And Results	
1.		Description of Standards and Results	
2.		eral Information	
	2.1.	Description of Device (EUT)	
	2.2.	Accessories of Device (EUT)	
		Fested Supporting System Details	
	2.3.	Block Diagram of connection between EUT and simulators	
	2.4.	Test mode Description	
	2.5.	Test Facility	
	2.6.	Measurement Uncertainty	
3.	Cond	lucted Disturbance At Mains Terminals Test	
	3.1.	Test Equipment	
	3.2.	Block Diagram of Test Setup	
	3.3.	Power Line Conducted Emission Test Limits	
	3.4.	Configuration of EUT on Test	
	3.5.	Operating Condition of EUT	
	3.6.	Test Procedure	
	3.7.	Conducted Disturbance at Mains Terminals Test Results	
4.	Radi	ated Disturbance Test	14
	4.1.	Test Equipment	14
	4.2.	Block Diagram of Test Setup	14
	4.3.	Test Standard	
	4.4.	Test Limit	
	4.5.	Configuration of EUT on Test	16
	4.6.	Operating Condition of EUT	
	4.7.	Test Procedure	16
	4.8.	Radiated Disturbance Test Results	17
5.	Harn	nonic Current Test	21
	5.1.	Test Equipment	21
	5.2.	Block Diagram of Test Setup	21
	5.3.	Test Standard	21
	5.4.	Harmonic Current Test Limits	21
	5.5.	Configuration of EUT on Test	22
	5.6.	Operating Condition of EUT	22
	5.7.	Test Procedure	22
	5.8.	Harmonic Current Test Results	23
6.	Volta	age Fluctuations & Flicker Test	24
	6.1.	Test Equipment	24
	6.2.	Block Diagram of Test Setup	24
	6.3.	Voltage Fluctuation and Flicker Test Limits	24
	6.4.	Test Standard	25

	6.5.	Configuration of EUT on Test	25
	6.6.	Operating Condition of EUT	25
	6.7.	Test Procedure	25
	6.8.	Voltage Fluctuation and Flicker Test Results	26
7.	IMM	UNITY PERFORMANCE CRITERIA	27
8.	Elect	rostatic Discharge Test	28
	8.1.	Test Equipment	28
	8.2.	Block Diagram of Test Setup	28
	8.3.	Electrostatic Discharge Test Limits	28
	8.4.	Configuration of EUT on Test	29
	8.5.	Operating Condition of EUT	29
	8.6.	Test Procedure	29
	8.7.	Electrostatic Discharge Test Results	30
9.	RF F	ield Strength Susceptibility Test	31
	9.1.	Test Equipment	
	9.2.	Block Diagram of Test Setup	31
	9.3.	RF Field Strength susceptibility Test Limits	32
	9.4.	Configuration of EUT on Test	
	9.5.	Operating Condition of EUT	32
	9.6.	Test Procedure	32
	9.7.	RF Field Strength Susceptibility Test Results	33
	9.8.	RF Field Strength Susceptibility Test Results	34
10.		rical Fast Transient/Burst immuNity Test	
			~ =
	10.1	. Test Equipment	35
	10.2	. Block Diagram of Test Setup	35
	10.2 10.3	. Block Diagram of Test Setup . Electrical Fast Transient/Burst Test Limits	35 36
	10.2 10.3 10.4	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> </ul>	35 36 36
	10.2 10.3 10.4 10.5	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> </ul>	35 36 36 36
	10.2 10.3 10.4 10.5 10.6	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> </ul>	35 36 36 36 36
	10.2 10.3 10.4 10.5 10.6 10.7	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> </ul>	35 36 36 36 36 37
11.	10.2 10.3 10.4 10.5 10.6 10.7 <b>Surg</b>	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> </ul>	35 36 36 36 36 37 <b>38</b>
11.	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> </ul>	35 36 36 36 36 37 <b> 38</b> 38
11.	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> <li>Block Diagram of Test Setup</li> </ul>	35 36 36 36 36 37 <b> 38</b> 38
11.	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> <li>Block Diagram of Test Setup</li> <li>Surge Test Limits</li> </ul>	35 36 36 36 36 37 <b> 38</b> 38 38 39
11.	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> <li>Block Diagram of Test Setup</li> <li>Surge Test Limits</li> <li>Configuration of EUT on Test</li> </ul>	35 36 36 36 37 <b>38</b> 38 38 39 39
11.	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> <li>Block Diagram of Test Setup</li> <li>Surge Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> </ul>	35 36 36 36 37 <b>38</b> 38 38 39 39 39
11.	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li></ul>	35 36 36 36 37 <b>38</b> 38 38 39 39 39 39
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li></ul>	35 36 36 36 37 <b> 38</b> 38 38 39 39 39 39 39 39
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7. <b>Injec</b>	<ul> <li>Block Diagram of Test Setup</li></ul>	35 36 36 36 37 <b>38</b> 38 38 39 39 39 39 39 39
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7. <b>Injec</b> 12.1.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> <li>Surge Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of Test Setup</li> <li>Surge Test Limits</li> <li>Operating Condition of EUT</li> <li>Surge Test Limits</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Surge Test Results</li> <li>Test Procedure</li> <li>Surge Test Results</li> <li>Test Results</li> <li>Test Results</li> <li>Test Results</li> <li>Test Results</li> </ul>	35 36 36 36 37 <b> 38</b> 38 39 39 39 39 39 39 39 39 39 39 40 <b> 41</b>
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7. <b>Injec</b> 12.1. 12.2.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li> <li>e test</li> <li>Test Equipments</li> <li>Block Diagram of Test Setup</li> <li>Surge Test Limits</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Surge Test Limits</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Surge Test Limits</li> <li>Test Procedure</li> <li>Derating Condition of EUT</li> <li>Test Procedure</li> <li>Block Diagram of Test Setup</li> <li>Test Procedure</li> <li>Burge Test Results</li> <li>Test Results</li> <li>Test Results</li> <li>Test Results</li> <li>Block Diagram of Test Setup</li> </ul>	35 36 36 36 37 <b> 38</b> 38 38 39
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7. <b>Injec</b> 12.1. 12.2. 12.3.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li></ul>	35 36 36 36 37 <b> 38</b> 38 38 39 39 39 39 39 39 39 39 39 39 39 39 40 <b> 41</b> 41 41
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7. <b>Injec</b> 12.1. 12.2. 12.3.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li></ul>	35 36 36 36 37 <b>38</b> 38 38 39 39 39 39 39 39
	10.2. 10.3. 10.4. 10.5. 10.6. 10.7. <b>Surg</b> 11.1. 11.2. 11.3. 11.4. 11.5. 11.6. 11.7. <b>Injec</b> 12.1. 12.2. 12.3. 12.4. 12.5.	<ul> <li>Block Diagram of Test Setup</li> <li>Electrical Fast Transient/Burst Test Limits</li> <li>Configuration of EUT on Test</li> <li>Operating Condition of EUT</li> <li>Test Procedure</li> <li>Electrical Fast Transient/Burst immunity Test Results</li></ul>	35 36 36 36 37 <b>38</b> 38 38 39 39 39 39 39 39

	12.7. Injected currents susceptibility Test Results	43
13.	Magnetic Field Immunity Test	44
	13.1. Test Equipments	
	13.2. Block Diagram of Test Setup	
	13.3. magnetic field Test Limits	
	13.4. Configuration of EUT on Test	
	13.5. Operating Condition of EUT	
	13.6. Test Procedure	45
	13.7. Magnetic field immunity Test Results	
14.	Voltage dips and interruptions test	47
	14.1. Test Equipments	47
	14.2. Block Diagram of Test Setup	47
	14.3. Voltage dips and interruptions Test Limits	
	14.4. Configuration of EUT on Test	
	14.5. Operating Condition of EUT	
	14.6. Test Procedure	
	14.7. Voltage dips and interruptions Test Results	
15.	Photograph	50
	15.1. Photos of Radiated Disturbance Test (In Semi Anechoic Chamber)	
	15.2. Photos of Electrostatic Discharge Test	
	15.3. Photo of RF Field Strength Susceptibility test	51
16.	Photos Of The EUT	52

### TEST REPORT DECLARATION

Applicant	Shenzhen Yostand Technology Co., Ltd.			
	10th Floor, Mingzhuo Building, MingzhuoXing Industrial Zone,			
Address	: Guangming Street, Guangming New District, Shenzhen, Guangdong			
	Province, China.			
Manufacturer	: Henan Bingzun Industrial Co., LTD.			
Address	50 meters next to the south of Guihua Villa, Xin'an Industry Cluster District,			
Address	· Luoyang City, Henan Province, China			
EUT Description	: Infrared Thermometer			
	(A) Model No. : ET01			
	(B) Trademark : yostand			

Measurement Standard Used:

#### EN 61000-6-3:2007 + A1:2011 EN 61000-6-1:2007

The device described above is tested by Shenzhen Alpha Product Testing Co., Ltd. to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The test results are contained in this test report and Shenzhen Alpha Product Testing Co., Ltd. is assumed full responsibility for the accuracy and completeness of test. Also, this report shows that the EUT is technically compliant with the EN 61000-6-3 and EN 61000-6-1 requirements.

This report applies to above tested sample only. This report shall not be reproduced in parts without written approval of Shenzhen Alpha Product Testing Co., Ltd.

Tested by (name + signature):	Ben Sun Project Engineer	Ben Repercerties
Approved by (name + signature):	Simple Guan Project Manager	ALPHA TESTING
Date of issue:	May 11, 2020	****

# **Revision History**

Revision	Issue Date	Revisions	Revised By
V0	May 11, 2020	Initial released Issue	Ben Sun

## 1. SUMMARY OF STANDARDS AND RESULTS

## 1.1.Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below:

EMISSION					
Description of Test Item	Standard			Limits	Results
Conducted disturbance at mains terminals	EN 61000-6-3:2007 + A1: 2011		Class B		N/A
Conducted disturbance at telecommunication port	EN 61000-6-3:2007 + 2011	A1:	Class B		N/A
Radiated disturbance	EN 61000-6-3:2007 + 2011	A1:	Class B		Р
Harmonic current emissions	EN 61000-3-2:2014			Class B	N/A
Voltage fluctuations & flicker	EN 61000-3-3:2013			Class B	N/A
IN	AMUNITY (EN 61000-6	5-1: 2007)			
Description of Test Item	Standard	Perform ce Criter		Observation Criteria	Results
Electrostatic discharge (ESD)	IEC 61000-4-2:2008	В		А	Р
Radio-frequency, Continuous radiated disturbance	IEC 61000-4-3:2006+ A1:2007 + A2:2010	А		А	Р
Electrical fast transient (EFT)	IEC 61000-4-4:2012	В		N/A	N/A
Surge (Input a.c. power port)		В		N/A	N/A
Surge(Telecommunication port)	IEC 61000-4-5:2014	В		N/A	N/A
Radio-frequency, Continuous conducted disturbance	IEC 61000-4-6:2013	A		N/A	N/A
Power frequency magnetic field	IEC 61000-4-8:2009	9 A		N/A	N/A
Voltage dips, >95% reduction		В		N/A	N/A
Voltage dips, >95% reduction	IEC 61000 4 11:2004	В		N/A	N/A
Voltage dips, 30% reduction	IEC 61000-4-11:2004			N/A	N/A
Voltage interruptions		С		N/A	N/A
Note:1. P is an abbreviation for Pass.2. F is an abbreviation for Fail.3. N/A is an abbreviation for Not Applicable.					

## 2. GENERAL INFORMATION

Description	:	Infrared Thermometer
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Model Number : ET01 Diff : N/A

Test Voltage	:	DC 3V From Battery
EUT Information	:	Input: 3V

Highest frequency	:	Less than 108MHz
Trademark	:	yostand

Software version	:	N/A
Hardware version	:	N/A

NoteThe Co-license is based on report A2003133-C01-R01. The new model<br/>ET01 Co-license is the same as the original model YS-ET01 mentioned in<br/>the test report A2003133-C01-R01. Except for the manufacturer "Henan<br/>Bingzun Industrial Co., Ltd.", no further testing is required.

2.2. Accessories of Device (EUT)

Power Source : N/A

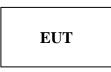
# 2.1.Tested Supporting System Details

No.	Description	Manufacturer	Model	Serial Number
1	Battery	Panasonic	R03PNU	N/A

2.3.Block Diagram of connection between EUT and simulators

For Test

For Working Mode



	Signal Cable Description of the above Support Units							
No.	Port Name	Cable	Length	Shielded (Yes or No)	Detachable (Yes or No)			
(a)	N/A	N/A	N/A	N/A	N/A			

**EUT: Infrared Thermometer** 

#### 2.4.Test mode Description

No.	Test Mode	Test Voltage
1.	Working	DC 3V From Battery

### 2.5.Test Facility

Shenzhen Alpha Product Testing Co., Ltd.

Building i, No.2, Lixin Road, Fuyong Street, Bao'an District, 518103, Shenzhen, Guangdong, China

## 2.6.Measurement Uncertainty

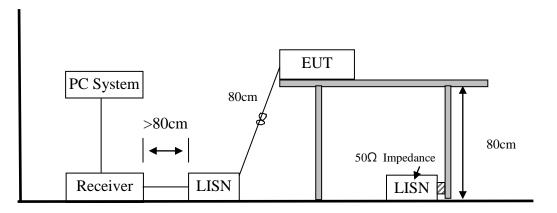
Item	MU	Remark
Uncertainty for Conducted Emission Test	2.74dB	
Uncertainty for Radiation Emission test in 3m chamber	3.77dB	Polarize: V
(30MHz to 1GHz)	3.80dB	Polarize: H
Uncertainty for Radiation	4.16dB	Polarize: H
Emission test in 3m chamber (1GHz to 25GHz)	4.13dB	Polarize: V
Uncertainty for radio frequency	$5.4 \times 10^{-8}$	
Uncertainty for conducted RF Power	0.37dB	

# 3. CONDUCTED DISTURBANCE AT MAINS TERMINALS TEST

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Test Receiver	Rohde & Schwarz	ESCI	101165	2019.09.05	1 Year
2.	L.I.S.N.#1	Schwarzbeck	NSLK8126	8126466	2019.09.05	1 Year
3.	L.I.S.N.#2	ROHDE&SCH WARZ	ENV216	101043	2019.09.05	1 Year
4.	Pulse Limiter	Schwarzbeck	9516F	9618	2019.09.05	1 Year

### 3.1.Test Equipment

## 3.2.Block Diagram of Test Setup



### 3.3.Power Line Conducted Emission Test Limits

	Maximum RF Line Voltage			
Frequency	Quasi-Peak Level	Average Level		
	dB(µV)	dB(µV)		
150kHz ~ 500kHz	66 ~ 56*	56 ~ 46*		
500kHz ~ 5MHz	56	46		
5MHz ~ 30MHz	60	50		

Notes: 1. Emission level=Read level + LISN factor-Preamp factor + Cable loss

- 2. \* Decreasing linearly with logarithm of frequency.
- 3. The lower limit shall apply at the transition frequencies.

#### 3.4. Configuration of EUT on Test

The following equipment are installed on conducted disturbance at mains terminals to meet the EN 55014-1 requirement and operating regulations in a manner which tends to maximize its emission characteristics in a normal application.

#### 3.5. Operating Condition of EUT

- (1) Setup the EUT as shown as Section 3.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### **3.6.Test Procedure**

- (1) The EUT was placed on a non-metallic table, 80cm above the ground plane. The EUT Power connected to the power mains through a line impedance stabilization network (L.I.S.N. 1#). This provided a 50-ohm coupling impedance for the EUT (Please refer to the block diagram of the test setup and photographs). The other peripheral devices power cord connected to the power mains through a line impedance stabilization network (L.I.S.N.#2). Both sides of power line were checked for maximum conducted interference. In order to find the maximum emission, the relative positions of equipments and all of the interface cables were changed according to EN 61000-6-3 on Conducted Disturbance at Mains Terminals test.
- (2) The frequency range from 150kHz to 30MHz is checked, the bandwidth of test receiver (R&S TEST RECEIVER ESCI) is set at 9kHz.
- (3) The test results are reported on Section 3.7.

### 3.7.Conducted Disturbance at Mains Terminals Test Results

EUT	:	Infrared Thermometer	Test Date : N	J∕A		
M/N	:	YS-ET01	Temperature : N	√A		
Test Engineer	:	N/A	Humidity : N	√A		
Test Voltage	:	N/A	Pressure : N	Ŋ∕A		
Test Mode	:	N/A				
Test Results : N/A						
Note: Not applicable for equipment operated with PC, battery, or Power Supply.						

# 4. RADIATED DISTURBANCE TEST

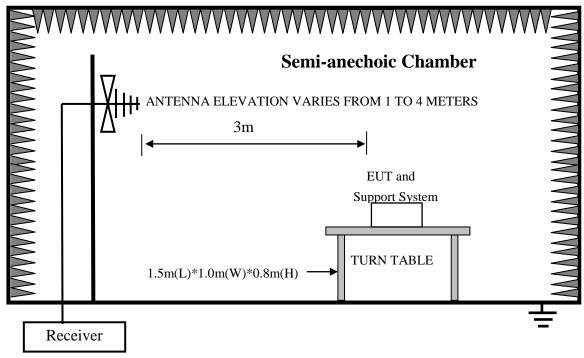
### 4.1.Test Equipment

For frequency range 30MHz~1GHz (At Semi Anechoic Chamber)							
Item	Equipment Manufacturer Model No. Serial No. Last Cal. Cal. Interval						
1	Test Receiver	Rohde&Schwarz	ESR	1316.3003K0 3-102082-Wa	2019.09.06	1 Year	
2	Bilog Antenna	Schwarzbeck	VULB 9168	9168-438	2018.04.13	2 Year	

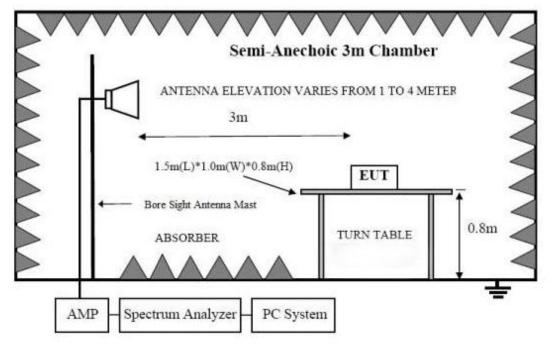
For frequency range above 1GHz (At Semi Anechoic Chamber)							
Item	Equipment	Manufacturer	Last Cal.	Cal. Interval			
1	Spectrum Analyzer	Agilent	E4407B	MY49510055	2019.09.06	1 Year	
2	Horn Antenna	Schwarzbeck	BBHA 9120 D	BBHA 9120 D(1201)	2018.04.13	2 Year	
3	Amplifier	Agilent	8449B	3008A02664	2019.09.06	1 Year	

## 4.2.Block Diagram of Test Setup

In Semi Anechoic Chamber (3m) Test Setup Diagram for 30MHz~1000MHz



In Semi Anechoic Chamber (3m) Test Setup Diagram for Above 1GHz



#### 4.3.Test Standard

EN 61000-6-3:2007 + A1:2011, Class B

#### 4.4.Test Limit

Frequency MHz	Distance (Meters)	Field Strengths Limits dB(µV)/m
$\frac{30}{230} \sim 230$	· · · · · · · · · · · · · · · · · · ·	40
230 ~ 100		47
1000 ~ 300	0 3	70(Peak) 50(Average)
3000 ~ 600	0 3	74(Peak) 54(Average)

Notes:

1. Emission level = Read level + Antenna Factor - Preamp Factor + Cable Loss

2. The smaller limit shall apply at the cross point between two frequency bands.

3. Distance is the distance in meters between the measuring instrument, antenna and the closest point of any part of the device or system.

#### 4.5.Configuration of EUT on Test

The following equipment are installed on Radiated Emission Test to meet the EN 61000-6-3 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 4.6.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 4.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

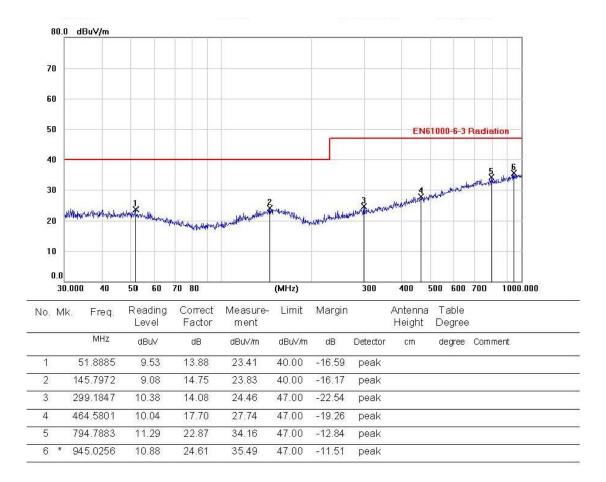
#### 4.7.Test Procedure

- (1) The EUT was placed on a non-metallic table, 80 cm above the ground plane inside a semi-anechoic chamber. An antenna was located 3m from the EUT on an adjustable mast. A pre-scan was first performed in order to find prominent radiated emissions. For final emissions measurements at each frequency of interest, the EUT were rotated and the antenna height was varied between 1m and 4m in order to maximize the emission. Measurements in both horizontal and vertical polarities were made and the data was recorded. In order to find the maximum emission, the relative positions of equipments and all the interface cables were changed according to EN 61000-6-3 on Radiated Disturbance test.
- (2) The frequency range from 30MHz to 1000MHz is checked, the bandwidth of test receiver (R&S TEST RECEIVER ESCI) is set at 120kHz.
- (3) The resolution bandwidth of the Agilent Spectrum Analyzer E4407B was set at 1MHz. (For above 1GHz)
- (4) The frequency range from 30MHz to 1000MHz was pre-scanned with a peak detector and all final readings of measurement from Test Receiver are Quasi-Peak values, all measurement distance is 3m in 3m semi anechoic chamber.
- (5) The frequency range from 1GHz to 6GHz was checked with peak and average detector, measurement distance is 3m in 3m chamber.
- (6) The test results are reported on Section 4.8.

### 4.8.Radiated Disturbance Test Results

For below 1G rad	iated disturbance test result:				
EUT	: Infrared Thermometer	Test Date : 2020.03.17			
M/N	: YS-ET01	Temperature : 24°C			
Test Engineer	: Korol Zhong	Humidity : 56%			
Test Voltage	: DC 3V From Battery	Pressure : 101.6Kpa			
Test Mode	: Working				
Test Results	: PASS				
Note: 1. The test	Note: 1. The test results are listed in next pages.				
2. If the li	2. If the limits for the measurement with the quasi-peak detector are met when using a				
receiver w	receiver with a peak detector, the test unit shall be deemed to meet both limits and the				
measurem	ent with the quasi-peak detector need	ed not be carried out.			

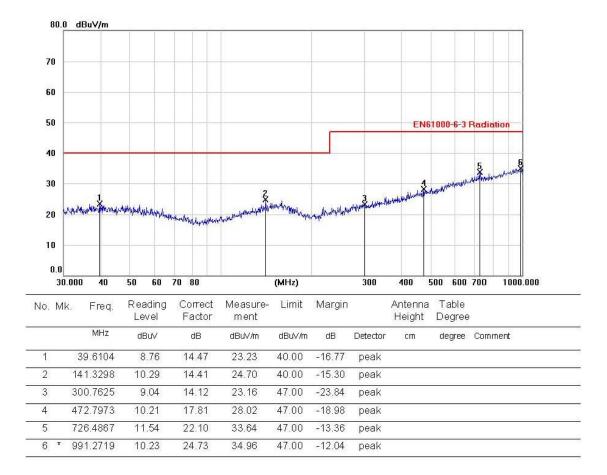
Antenna polarity: Vertica	Antenna	polarity:	Vertical
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Note:1. \*:Maximum data; x:Over limit; !:over margin.

2.Measurement=Reading Level+Correct Factor; Correct Factor=Antenna Factor+Cable Loss.

Antenna	polarity	: Horizontal
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Note:1. \*:Maximum data; x:Over limit; I:over margin.

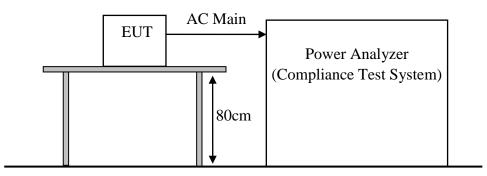
2.Measurement=Reading Level+Correct Factor; Correct Factor=Antenna Factor+Cable Loss.

For ab	For above 1G radiated disturbance test result:				
EUT	: Infrared Thermo	meter	Test Date :	N/A	
M/N : YS-ET01		,	Temperature :	N/A	
Test Engineer     : N/A     Humidity     : N/A		N/A			
Test Voltage : N/A			Pressure :	N/A	
Test M	Test Mode : N/A				
Test R	Test Results : N/A				
	The highest frequency of the internal sources of the EUT is less than 108 MHz, the			8 MHz, the	
Note:	measurement shall only be made up to 1 GHz. So the frequency rang above 1GHz				
	radiation test not applicable.				

## 5. HARMONIC CURRENT TEST

Iter	n Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1	Harmonics Flicker Analyser	Voltech	PM6000	20000670049 5	2019.09.06	1 Year

### 5.2.Block Diagram of Test Setup



### 5.3.Test Standard

EN 61000-3-2:2014; Class A

### 5.4.Harmonic Current Test Limits

For Class A equipment:

Harmonic order	Maximum permissible harmonic current
101.2 Sec. 101.2	A A armonics
3	2,30
3 5	1,14
7	0,77
9	0,40
11	0,33
13	0,21
$15 \le n \le 39$	0,15 <u>15</u>
Even h	armonics
2	1,08
4	0,43
4 6	0,30
$8 \le n \le 40$	0,23 <del>8</del>

for Class B equipment:

The harmonics of the input current shall not exceed the values given in Class A equipment limit multiplied by a factor of 5.4.

#### 5.5.Configuration of EUT on Test

The following equipment are installed on Configuration of EUT on Test to meet the EN61000-3-2 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 5.6.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 5.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### **5.7.Test Procedure**

- (1) The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the necessary for the EUT to be exercised.
- (2) The test results are reported on Section 5.8.

### 5.8.Harmonic Current Test Results

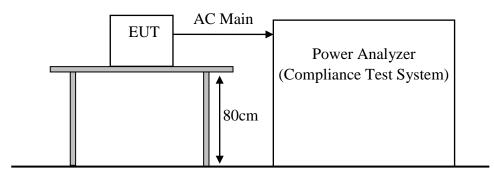
EUT	:	Infrared Thermometer	Test Date	:	N/A
M/N	:	YS-ET01	Temperature	:	N/A
Test Engineer	:	N/A	Humidity	:	N/A
Test Voltage	:	N/A	Pressure	:	N/A
Test Mode : N/A					
Test Results : N/A					
Note: Not applicable for equipment operated with battery power supply.					

# 6. VOLTAGE FLUCTUATIONS & FLICKER TEST

6.1.Test E	quipment
------------	----------

Ι	ltem	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
	1	Harmonics Flicker Analyser	Voltech	PM6000	20000670049 5	2019.09.12	1 Year

## 6.2.Block Diagram of Test Setup



## 6.3.Voltage Fluctuation and Flicker Test Limits

Test Item	Limit	Note
P <sub>st</sub>	1.0	P <sub>st</sub> means Short-term flicker indicator
P <sub>lt</sub>	0.65	P <sub>lt</sub> means long-term flicker indicator
T <sub>dt</sub>	0.2	T <sub>dt</sub> means maximum time that dt exceeds 3%
$d_{max}(\%)$	4%	d <sub>max</sub> means maximum relative voltage change.
d <sub>c</sub> (%)	3.3%	d <sub>c</sub> means relative steady-state voltage change.

6.4. Test Standard

EN 61000-3-3:2013

#### 6.5.Configuration of EUT on Test

The following equipment are installed on Harmonic Current Test to meet the EN61000-3-3 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 6.6.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 6.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### 6.7.Test Procedure

- (1) The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal conditions During the flick measurement; the measure time shall include that part of whole operation changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.
- (2) The test results are reported on Section 6.8.

## 6.8. Voltage Fluctuation and Flicker Test Results

EUT	:	Infrared Thermometer	Test Date	:	N/A
M/N	:	YS-ET01	Temperature	:	N/A
Test Engineer	:	N/A	Humidity	:	N/A
Test Voltage	:	N/A	Pressure	:	N/A
Test Mode	:	N/A			
Test Results	:	N/A			
Note: Not applicable for equipment operated with battery power supply.					

## 7. IMMUNITY PERFORMANCE CRITERIA

#### Performance Level

The test results shall be classified in terms of the loss of function or degradation of performance of the equipment under test, relative to a performance level by its manufacturer or the requestor of the test, or the agreed between the manufacturer and the purchaser of the product.

Definition related to the performance level:

- 1. Based on the used product standard
- 2.Based on the declaration of the manufacturer, requestor or purchaser

#### Performance criterion A

When seen from the normal viewing distance, the EUT shall operate with no change beyond the manufacturer's specification, in flicker, colour, focus and jitter (except for the power frequency magnetic field test).

#### Power frequency magnetic field test

For CRT monitors, the following also applies: The jitter shall be measured using a measuring microscope as specified in 6.6.14 of ISO 9241-3.

The jitter (in mm) shall not exceed the value  $\frac{(\text{character height in mm} + 0,3) \times 2,5}{33.3}$  when the CRT

monitor is immersed in a continuous magnetic field of 1A/m (r.m.s.) at one of the power frequencies of 50Hz.

Alternatively, a field of 50A/m may be applied, and a transparent graduated mask used to assess the jitter. In that case, the jitter shall not exceed 50 times the value in the above formula.

NOTE-This test level is used to simplify the measurement of jitter. Lesser values of the test level may be used if non-linearity is experienced, due to, for example, saturation of screening material.

The EUT shall be tested in two positions, both perpendicular to the magnetic field.

#### Performance criterion B

Screen disturbances during the application of the test are permissible.

#### Performance criterion C

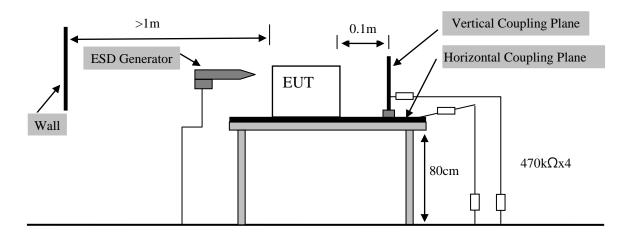
Failures which are not self-recovered after removal of the external disturbance, but which can be recovered to normal operation by reset or reboot are permissible.

## 8. ELECTROSTATIC DISCHARGE TEST

### 8.1.Test Equipment

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1	ESD Tester	HAEFELY	PESD1610	H310546	2019.09.12	1 Year

#### 8.2.Block Diagram of Test Setup



## 8.3.Electrostatic Discharge Test Limits

Test Type	Test Level	Performance Criterion
Air Discharge	2, 4, 8KV	В
Contact Discharge	2, 4KV	В

Notes: 1. Test set-up reference IEC 61000-4-2:2008

#### 8.4.Configuration of EUT on Test

The following equipment are installed on Electrostatic Discharge Test to meet the IEC 61000-4-2 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 8.5.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 8.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### 8.6.Test Procedure

#### (1) Air Discharge:

The test was applied on non-conductive surfaces of EUT. The round discharge tip of the discharge electrode was approached as fast as possible to touch the EUT. After each discharge, the discharge electrode was removed from the EUT. The generator was re-triggered for a new single discharge and repeated 20 times (10 with positive and 10 negative with positive ) for each pre-selected test point. This procedure was repeated until all the air discharge completed.

#### (2) Contact Discharge:

All the procedure was same as Section 8.6.1. Except that the generator was re-triggered for a new single discharge and repeated 20 times for each pre-selected test point. The tip of the discharge electrode was touching the EUT before the discharge switch was operated.

#### (3) Indirect discharge for horizontal coupling plane:

At least 20 single discharges (10 with positive and 10 negative with positive) were applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1m from the EUT and with the discharge electrode touching the coupling plane.

(4) Indirect discharge for vertical coupling plane:

At least 20 single discharge (10 with positive and 10 negative with positive) were applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, was placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges were applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

# 8.7.Electrostatic Discharge Test Results

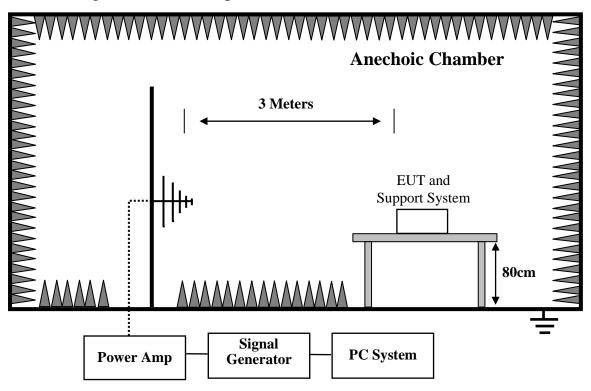
EUT		: Infrared Thermometer	•	Test Date : 2020.03.17					
M/N		: YS-ET01		Tem	perature : 2	24℃			
Test Er	st Engineer : Korol Zhong Humi				idity : 5	6 %			
Test Vo	oltage	DC 3V From Battery		Press	ure : 1	01.6Kpa			
Test M	ode	: Working							
Test Re	esults	: PASS							
Disc	charge	Type Of Discharge	Dischargeable Po	vinte	Perfo	rmance			
Volta	ige (kV	) Type of Discharge	Dischargeable 1 onits		Required	Observation			
	$\pm 2$	Contact	N/A		В	N/A			
	$\pm 4$	Contact	N/A		В	N/A			
-	$\pm 2$	Air	1, 2, 3		В	А			
	$\pm 4$	Air	1, 2, 3		В	А			
:	$\pm 8$	Air	1, 2, 3		В	А			
:	$\pm 2$	HCP-Bottom	Edge of the HCP		В	А			
:	$\pm 4$	HCP-Bottom	Edge of the HCP		В	А			
$\pm 2$		VCP-Front	Center of the VCP		В	А			
$\pm 4$		VCP-Front	Center of the VCP		В	А			
-	$\pm 2$	VCP-Left	Center of the VCP		В	А			
:	$\pm 4$	VCP-Left	Center of the VCP		В	А			
:	$\pm 2$	VCP-Back	Center of the VCP		В	А			
:	$\pm 4$	VCP-Back	Center of the VCP		В	A			
-	$\pm 2$	VCP-Right	Center of the VCP		В	А			
:	$\pm 4$	VCP-Right	Center of the VC	СР	В	А			
		Dischar	rge Points Descript	ion					
<u>1</u>	LED	Screen							
2	Butto	n							
3	Gap								
1. For the time interval between successive single discharges an initial value of one second.						value of one			
Nota	2.1	2. For Air Discharge each Point Positive 10 times and negative 10 times discharge.							
Note:		For Contact Discharge each	h point positive 10 t	imes a	nd negative 10	times			
		charge.							
		EUT is pure plastic shell, s	o is not apply to cor	ntact d	ischarge.				
Remarl	k: Cla	ass A is no function loss.							

## 9. RF FIELD STRENGTH SUSCEPTIBILITY TEST

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	vector Signal Generator	Agilent	E4438C	US44271917	2019.09.06	1 Year
2.	Power meter	Agilent	E4419B	GB40202122	2019.09.06	1 Year
3.	Power Sensor	Agilent	E9300A	MY41496625	2019.09.06	1 Year
4.	RF power Amplifier	OPHIR	5225R	1045	2019.09.06	1 Year
5.	RF power Amplifier	OPHIR	5273R	1018	2019.09.06	1 Year
6.	Antenna	SCHWARZBECK	STLP9128E- special	STLP9128E s#139	N/A	NCR
7.	Antenna	SCHWARZBECK	STLP9128E- special	STLP 9149 #456	N/A	NCR

## 9.1.Test Equipment

## 9.2.Block Diagram of Test Setup



#### 9.3.RF Field Strength susceptibility Test Limits

Test Specifications	Test Level	Performance Criterion
80MHz-1000MHz	3V/m (r.m.s.)	А

Notes: 1. Test set-up reference IEC 61000-4-3:2006 + A1:2007 + A2:2010

### 9.4.Configuration of EUT on Test

The following equipment are installed on RF Field Strength Susceptibility Test to meet the IEC 61000-4-3 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 9.5. Operating Condition of EUT

- (1) Setup the EUT as shown as Section 9.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### 9.6.Test Procedure

- (1) Testing was performed in a Fully anechoic chamber as recommended by IEC 61000-4-3.
   The EUT was placed on an 80 cm high non-conductive table located in the area of field uniformity. The radiating antenna was placed 3m in front of the EUT and Support
- (2) system, and dwell time of the radiated interference was controlled by an automated, computer-controlled system.

The signal source was stepped through the applicable frequency range at a rate no faster than 1% of the fundamental. The signal was amplitude modulated 80% over the

- (3) frequency range 80 MHz to 1GHz & 1.4GHz to 2GHz at a level of 3 V/m. The signal was amplitude modulated 80% over the frequency range 2GHz to 2.7GHz at a level of 1 V/m The dwell time was set at 3 s. Field presence was monitored during testing via a field probe placed in close proximity to the EUT.
- (4) Throughout testing, the EUT was closely monitored for signs of susceptibility. The test was performed with the antennae oriented in both a horizontal and vertical polarization.

The seaming conditions are as follows.					
Condition of Test	Require of Test				
Test Fielded Strength	3 V/m & 1V/m				
Radiated Signal	80% amplitude modulated with a 1kHz sine wave				
Scanning Frequency	80 - 1000 MHz, 1.4GHz-2GHz, 2GHz-2.7GHz				
Sweeping time of radiated	0.0015 decade/s				
Dwell Time	3 Sec.				

(5) All the scanning conditions are as follows:

## 9.7.RF Field Strength Susceptibility Test Results

EUT	:	Infrared Thern	nometer		Test Date	: 2020.03.17
M/N	:	YS-ET01			Temperature	: 24°C
Test Engineer	:	Korol Zhong			Humidity	: 56 %
Test Voltage		DC 3V From I	Battery		Pressure	: 101.6Kpa
Frequency Range	:	80 MHz -1000	MHz, 1.4GHz -	– 2GHz	Field Strength	: 3V/m
Test Mode	:	Working				
Test Results	:	PASS				
Modulation:		🗹 AM	□ Pulse	□ n	one 1 kHz	80%
		Fr	equency Range	e :80 MHz -1	000MHz, 1.4G	Hz – 2GHz
Steps		1%				
		Hor	Horizontal		ertical	Result
		Required	Observation	Required	Observation	(Pass / Fail)
Front		A	А	А	A	Pass
Right		A	А	А	A	Pass
Rear		A	А	А	A	Pass
Left		A	А	A A Pass		
Remark: Class	Remark: Class A is no function loss					

## 9.8.RF Field Strength Susceptibility Test Results

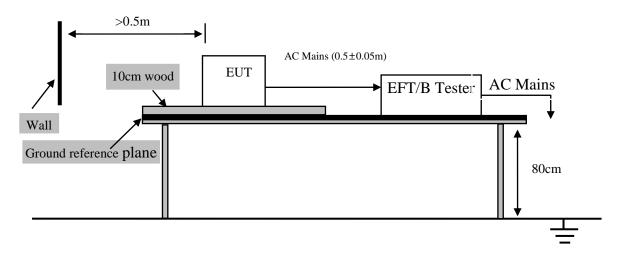
EUT	:	Infrared Thern	nometer		Test Date	: 2020.03.17
M/N	:	YS-ET01			Temperature	: 24°C
Test Engineer	:	Korol Zhong			Humidity	: 56 %
Test Voltage		DC 3V From I	Battery		Pressure	: 101.6Kpa
Frequency Range	:	2GHz-2.7GHz	-			: 1V/m
Test Mode	:	Working				
Test Results	:	PASS				
Modulation:		🗹 AM	□ Pulse	□ n	one 1 kHz	80%
			Freque	ency Range	2GHz-2.7GHz	
Steps		1%				
		Hor	Horizontal		ertical	Result
		Required	Observation	Required	Observation	(Pass / Fail)
Front		А	А	А	A	Pass
Right		A	А	А	A	Pass
Rear		A	А	А	A	Pass
Left		A	А	A A Pass		Pass
Remark: Class	Ai	s no function lo	SS			

# **10.ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST**

## 10.1.Test Equipment

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Multifunctio nal Compact Immunity Test system	3ctest	CCS 600	ES0801655	2019.09.05	1 Year
2.	Surge&EFT Coupling Decoupling Network	3ctest	SEPN 3832T	ES0951601	2019.09.05	1 Year
3.	Voltage variation and PF magnetic field regulating device	3ctest	VMT2216S	ES0441601	2019.09.06	1 Year
4.	Capacitive Coupling Clamp	3ctest	CCC 100	EC0441660	2019.09.06	1 Year

## 10.2.Block Diagram of Test Setup



#### 10.3. Electrical Fast Transient/Burst Test Limits

Test Specifications	Test Level	Performance Criterion
1.	2	2
2.	4	4
3.	6	8
4.	8	15
Х	Special	Special

Notes: 1. Test set-up reference IEC 61000-4-4:2012

### 10.4. Configuration of EUT on Test

The following equipment are installed on Electrical Fast Transient/Burst immunity Test to meet the IEC 61000-4-4 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

### 10.5.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 10.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

### 10.6.Test Procedure

The EUT and its simulators were placed on the ground reference plane and were insulated from it by a wood support 0.1m + 0.01m thick. The ground reference plane was 1m\*1m metallic sheet with 0.65mm minimum thickness. This reference ground plane was project

- (1) beyond the EUT by at least 0.1m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane was more than 0.5m. All cables to the EUT was placed on the wood support, cables not subject to EFT/B was routed as far as possible from the cable under test to minimize the coupling between the cables.
- 10.6.1. For input and AC power ports:

The EUT was connected to the power mains by using a coupling device that couples the EFT interference signal to AC power lines. Both positive transients and negative transients of test voltage were applied during compliance test and the duration of the test can't less than 1min. 10.6.2. For signal lines and control lines ports:

It's unnecessary to test.

10.6.3. For DC input and DC output power ports:

It's unnecessary to test.

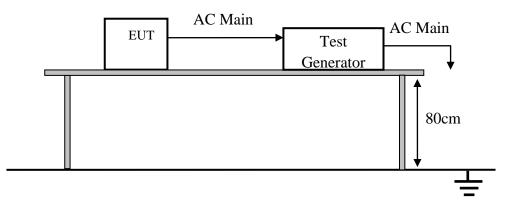
## 10.7.Electrical Fast Transient/Burst immunity Test Results

EUT	:	Infrared Thermometer	Test Date	:	N/A	
M/N	:	YS-ET01	Temperature	:	N/A	
Test Engineer	:	N/A	Humidity	:	N/A	
Test Voltage	:	N/A	Pressure	:	N/A	
Test Mode	:	N/A	·			
Test Results : N/A						
Note: Not app	Note: Not applicable for equipment operated with battery power supply.					

# **11.Surge Test**

# 11.1.Test Equipments

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Multifunctional Compact Immunity Test system	3ctest	CCS 600	ES0801655	2019.09.05	1 Year
2.	Surge&EFT Coupling Decoupling Network	3ctest	SEPN 3832T	ES0951601	2019.09.05	1 Year
3.	Voltage variation and PF magnetic field regulating device	3ctest	VMT2216S	ES0441601	2019.09.06	1 Year
4.	Capacitive Coupling Clamp	3ctest	CCC 100	EC0441660	2019.09.06	1 Year



#### 11.3.Surge Test Limits

Severity Level	Open-Circuit Test Voltage (kV)
1	0.5
2	1
3	2
4	4
*	Special

Notes: 1. Test set-up reference IEC 61000-4-5:2014

### 11.4.Configuration of EUT on Test

The following equipment are installed on Surge test to meet the IEC 61000-4-5 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

### 11.5.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 11.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

### 11.6.Test Procedure

For line-to-line coupling mode, provide a 1kV 1.2/50us voltage surge (at open-circuit

- condition) and 8/20us current surge to EUT selected points, and for active line / neutral lines to ground are same except test level is 2kV.
- (2) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are applied during test.
- (3) Different phase angles are done individually.
- (4) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

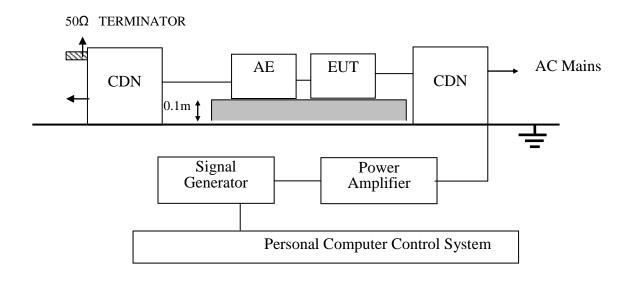
### 11.7.Surge Test Results

EUT	: Infrared Thermometer	Test Date	:	N/A
M/N	: YS-ET01	Temperature	:	N/A
Test Engineer	: N/A	Humidity	:	N/A
Test Voltage	: N/A	Pressure	:	N/A
Test Mode	: N/A			
Test Results	: N/A			
Note: Not applic	able for equipment operated with PC	, battery, or Power S	upply.	

# **12.INJECTED CURRENTS SUSCEPTIBILITY TEST**

Ite	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal.
m						Interval
1.	Conducted Immunity test System	SKET	CITS_150 K230M	SK2019101 001_CITS	2019.11.08	1 Year
2.	Fixed Coaxial Attenuator (6dB Attenuation)	CD	ATT-0675	120540086	2019.09.06	1 Year
3.	coupling-decoupli ng network (CDN)	CD	CDN M2/M3	2302	2019.09.06	1 Year
4.	Electromagnetic Injection Clamp (EMC-Clamp)	CD	EM-Clamp	0513A0312 01	2019.09.05	1 Year

## 12.1.Test Equipments



#### 12.3.Injected currents susceptibility Test Limits

Level	Voltage Level (e.m.f.) V
1	1
2	3
3	10
X	Special

Notes: 1. Test set-up reference IEC 61000-4-6:2013

### 12.4.Configuration of EUT on Test

The following equipment are installed on Electrostatic Discharge Test to meet the IEC 61000-4-6 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

### 12.5.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 12.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

### 12.6.Test Procedure

- (1) Let the EUT work in test mode and test it.
   The EUT are placed on an insulating support 0.1m high above a ground reference plane.
   CDN (coupling and decoupling device) is placed on the ground plane about 0.3m from
- (2) EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 10 and 30 mm (where possible).
- (3) The disturbance signal described below is injected to EUT through CDN.
- (4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- (5) The frequency range is swept from 0.150MHz to 80MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1kHz sine wave.

The rate of sweep shall not exceed 1.5\*10-3decades/s. Where the frequency is swept

- (6) incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- (7) Recording the EUT operating situation during compliance testing and decide the EUT
- (*immunity criterion*.

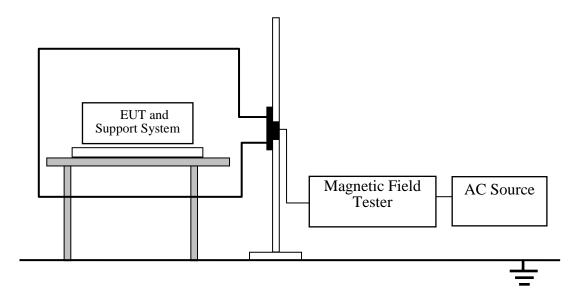
## 12.7.Injected currents susceptibility Test Results

EUT	: Infrared Thermometer	Test Date : N/A				
M/N	: YS-ET01	Temperature : N/A				
Test Engineer	: N/A	Humidity : N/A				
Test Voltage	: N/A	Pressure : N/A				
Test Mode	: N/A					
Test Results : N/A						
Note: Not applicable for equipment operated with battery power supply.						

# **13.Magnetic Field Immunity Test**

### 13.1.Test Equipments

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Multifunctional Compact Immunity Test system	3ctest	CCS 600	ES0801655	2019.09.05	1 Year
2.	Surge&EFT Coupling Decoupling Network	3ctest	SEPN 3832T	ES0951601	2019.09.05	1 Year
3.	Voltage variation and PF magnetic field regulating device	3ctest	VMT2216S	ES0441601	2019.09.06	1 Year
4.	Capacitive Coupli ng Clamp	3ctest	CCC 100	EC0441660	2019.09.06	1 Year



#### 13.3.magnetic field Test Limits

Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
Х	Special

Notes: 1. Test set-up reference IEC 61000-4-8:2009

#### 13.4.Configuration of EUT on Test

The following equipment are installed on Magnetic Field Immunity Test to meet the IEC 61000-4-8 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 13.5.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 13.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### 13.6.Test Procedure

The EUT was subjected to the test magnetic field by using the induction coil of standard

(1) dimensions (1m\*1m) and shown in Section 13.2. The induction coil was then rotated by 90 °in order to expose the EUT to the test field with different orientations.

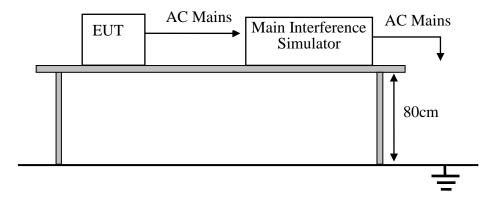
## 13.7.Magnetic field immunity Test Results

		1				
EUT	: Infrared Thermometer	Test Date : N/A				
M/N	: YS-ET01	Temperature : N/A				
Test Engineer	: N/A	Humidity : N/A				
Test Voltage	: N/A	Pressure : N/A				
Test Mode	Test Mode : N/A					
Test Results	Test Results : N/A					
The EUT not containing devices susceptible to magnetic fields, and Power-frequency						
Note: magnetic field test applicable only to EUT containing devices susceptible to magnetic						
fields, so the test not applicable.						

# 14. VOLTAGE DIPS AND INTERRUPTIONS TEST

## 14.1.Test Equipments

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Multifunctional Compact Immunity Test system	3ctest	CCS 600	ES0801655	2019.09.05	1 Year
2.	Surge&EFT Coupling Decoupling Network	3ctest	SEPN 3832T	ES0951601	2019.09.05	1 Year
3.	Voltage variation and PF magnetic field regulating device	3ctest	VMT2216S	ES0441601	2019.09.06	1 Year
4.	Capacitive Coupl ing Clamp	3ctest	CCC 100	EC0441660	2019.09.06	1 Year



#### 14.3.Voltage dips and interruptions Test Limits

Test Level %UT	Voltage dip and short interruptions %UT	Performance Criterion	Duration (in period)
0	100	В	0.5
0	100	В	1
70	30	С	25
0	100	С	250

Notes: 1. Test set-up reference IEC 61000-4-11:2004

#### 14.4.Configuration of EUT on Test

The following equipment are installed on Voltage dips and interruptions test to meet the IEC 61000-4-11 requirements and operating regulations in a manner that tends to maximize its emission characteristics in normal application.

#### 14.5.Operating Condition of EUT

- (1) Setup the EUT as shown as Section 14.2.
- (2) Turn on the power of all equipment.
- (3) Let the EUT work in test mode and 15 minutes before taking the test.

#### 14.6.Test Procedure

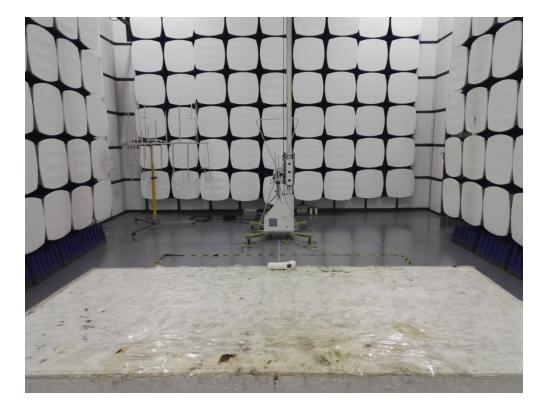
- (1) The interruption is introduced at selected phase angles with specified duration.
- (2) Record any degradation of performance.

## 14.7.Voltage dips and interruptions Test Results

EUT	: Infrared Thermometer	Test Date : N/A
M/N : YS-ET01		Temperature : N/A
Test Eng	gineer : N/A	Humidity : N/A
Test Vol	ltage : N/A	Pressure : N/A
Test Mode : N/A		
Test Results : N/A		
Note:	Not applicable for equipment operated with battery power supply.	

# **15.PHOTOGRAPH**

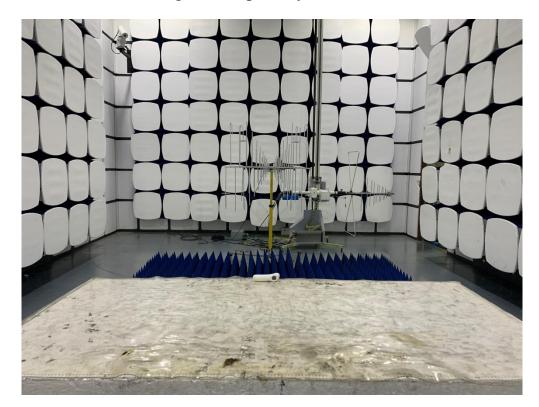
15.1.Photos of Radiated Disturbance Test (In Semi Anechoic Chamber)



15.2.Photos of Electrostatic Discharge Test



# 15.3.Photo of RF Field Strength Susceptibility test



### **16.PHOTOS OF THE EUT**



**EUT View** 



**EUT View** 

Page 53 of 57



**EUT View** 



**EUT View** 

Page 54 of 57



**EUT View** 

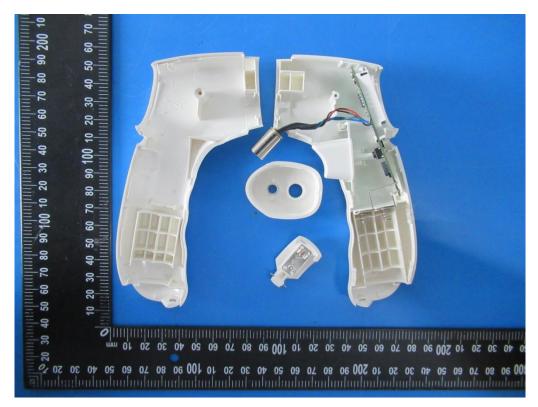


**EUT View** 



Page 55 of 57

**EUT View** 

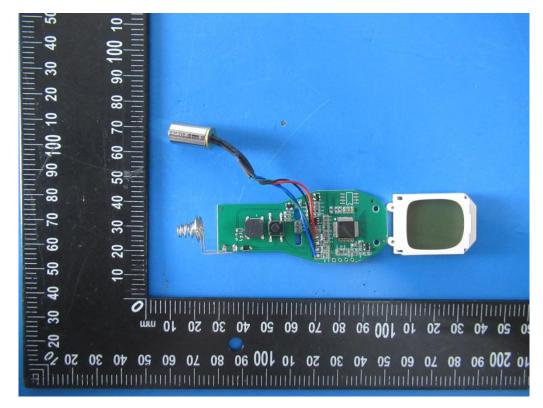


**EUT View** 

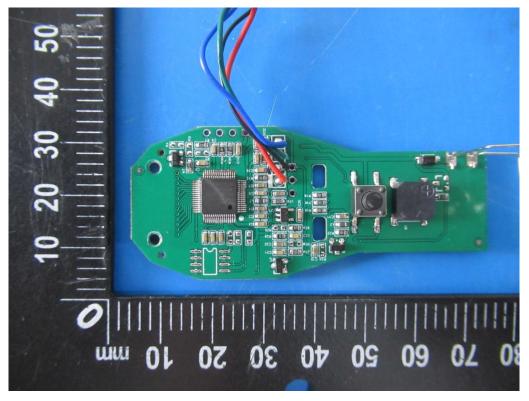
Page 56 of 57



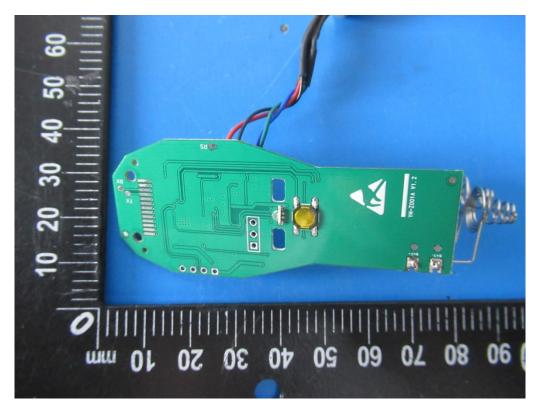
**EUT View** 



**EUT View** 



**EUT View** 



EUT View
----END OF REPORT----